

Laboratory	Delhi Test House, Plot No. 50, Phase-IV, Sector 57, HSIDC Industrial Area, Kundli, Sonipat, Haryana		
Accreditation Standard	ISO/IEC 17025: 2005		
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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
I. ELECTRO MEDICAL EQUIPMENT				
1.	Medical Electrical Equipment	Classification of ME Equipment and ME System	IEC 60601-1:2005	Qualitative
		ME Equipment Identification Marking and Documents	IEC 60601-1:2005	Qualitative
		Protection Against electrical Hazards from ME Equipment	IEC 60601-1: 2005	0 to 75 V 75 N
		Requirement Related to power Sources	IEC 60601-1: 2005	0 to 500 V 0 to 1000 W 0 to 20 A
		Classification of applied Parts	IEC 60601-1: 2005	Qualitative
		Limitation of Voltage Current of Energy	IEC 60601-1: 2005	0 to 250 V 0 to 5000 W 0 to 500 V
		Separation of Parts	IEC 60601-1: 2005	Qualitative
		Insulation	IEC 60601-1: 2005	2 MΩ to 2 GΩ
		Creepage Distance and air Clearance	IEC 60601-1: 2005	0 to 150 mm 0 to 25 mm
		Components and Wiring	IEC 60601-1: 2005	Qualitative
		Protection Against Mechanical Hazards of ME Equipment and ME System	IEC 60601-1: 2005	Qualitative
		Mechanical Hazards of ME Equipment	IEC 60601-1: 2005	Qualitative

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	Medical Electrical Equipment	Hazards associated with moving Parts	IEC 60601-1: 2005	Qualitative
		Hazards Associated With Surface Corners and edges	IEC 60601-1: 2005	Qualitative
		Instability Hazards	IEC 60601-1: 2005	0 to 20 °
		Hazards Associated with Support System	IEC 60601-1: 2005	Qualitative
		Protection Against Excessive Temperature and other Hazards	IEC 60601-1: 2005	0 to 400 °C
		Excessive Temperature in ME Equipment	IEC 60601-1: 2005	0 to 400 °C
		Fire Prevention	IEC 60601-1: 2005	0 to 100 % 0 to 400 °C
		Constructional Requirements of Fire Enclosure of ME Equipment	IEC 60601-1: 2005	Qualitative
		Constructional Requirements of Fire Enclosure of ME Equipment	IEC 60601-1: 2005	Qualitative
		Hazardous Situations and fault conditions for ME Equipment	IEC 60601-1: 2005	0 to 999.9 W
		Accuracy of controls and Instruments and protection against hazardous	IEC 60601-1: 2005	Qualitative
		Construction of ME Equipment	IEC 60601-1: 2005	20 cNm to 120 cNm, 1 Nm to 6 Nm

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II. AUDIO/VIDEO COMPONENTS AND PRODUCTS				
1.	Audio, Video electronic apparatus	Marking & Instruction	IS 616: 2010 IEC 60065: 2005 Clause. 5.0	0 to 1000 W 0 to 500 V 0 to 20 A
		Hazardous Radiations	IS 616: 2010 IEC 60065: 2005 Clause. 6	0 to 5 mR/Hr
		Heating under normal operating conditions	IS 616: 2010 IEC 60065: 2005 Clause. 7	25 °C to 200 °C
		Heat Resistance of Insulating material	IS 616: 2010 IEC 60065: 2005 Clause. 7.2	0 to 200 °C 0 to 100 mm,
		Construction requirement regard to protection against electric shock	IS 616: 2010 IEC 60065: 2005 Clause. 8	0 to 200 N 0 to 150 mm,
		Determination of Hazardous live parts	IS 616: 2010 IEC 60065: 2005 Clause. 9.1.1.11	0 to 20 mA
		Determination of Accessible parts	IS 616: 2010 IEC 60065: 2005 Clause. 9.1.1.2	Qualitative
		Opening of the enclosure	IS 616: 2010 IEC 60065: 2005 Clause. 9.13	Qualitative
		Terminals (Clause. 9.1.4)	IS 616: 2010 IEC 60065: 2005 Clause. 9.14	Qualitative
		Preset controls	IS 616: 2010 IEC 60065: 2005 Clause. 9.15	Qualitative

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	Audio, Video electronic apparatus	Withdrawal of main plug	IS 616: 2010 IEC 60065: 2005	0 to 500 V 0 to 1000 V 0 to 25 MHz, 1.2 Micros to 50 s
		Resistance to external forces	IS 616: 2010 IEC 60065: 2005 Clause. 9.17	Qualitative
		Humidity treatment	IS 616: 2010 IEC 60065: 2005 Clause. 10.2	Up to 50 °C Upto 98 % RH
		Insulation resistance and dielectric strength	IS 616: 2010 IEC 60065: 2005 Clause. 10.3	>2 MΩ 0 to 5 kV
		Electric shock hazard	IS 616: 2010 IEC 60065: 2005	0 to 10 mA
		Measurement of temperature rise	IS 616: 2010 IEC 60065: 2005 Clause. 11.2.1	Ambient to 200 °C
		Bump test	IS 616: 2010 IEC 60065: 2005 Clause. 12.1.1	Qualitative
		Impact test	IS 616: 2010 IEC 60065: 2005 Clause. 12.1.3	(50±1) mm dia 500 gm.
		Drop test	IS 616: 2010 IEC 60065: 2005 Clause. 12.1.14	Hardwood 13 mm on 19 mm to 20 mm
		Stress relief test	IS 616: 2010 IEC 60065: 2005 Clause. 12.1.5	0 to 400 °C
		Fixing of actuating element	IS 616: 2010 IEC 60065: 2005 Clause. 12.2	20 cNm to 120 cNm, 1 Nm to 6 Nm

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	Audio, Video electronic apparatus	Drawens	IS 616: 2010 IEC 60065: 2005 Clause. 12.4	0 to 200 N
		Clearance & creepage distance Determination of operating voltages	IS 616: 2010 IEC 60065: 2005 Clause. 13.2	0 to 1000 V DC, 0 to 750 V AC, 0 to 150 mm,
		Clearances	IS 616: 2010 IEC 60065: 2005 Clause. 13.3	0 to 150 mm 0 to 25 mm,
		Creepage distance	IS 616: 2010 IEC 60065: 2005 Clause. 13.4	0 to 150 mm 0 to 25 mm,
		Jointed insulation	IS 616: 2010 IEC 60065: 2005 Clause. 13.6	0 to 1000 °C 0 to 5 kV
		Enclosed sealed parts	IS 616: 2010 IEC 60065: 2005 Clause. 13.7	0 to 100 °C 0 to 5 kV
		Components	IS 616: 2010 IEC 60065: 2005 Clause. 14	Data verification
		Terminals	IS 616: 2010 IEC 60065: 2005 Clause. 15	20 cNm to 120 cNm, 1 Nm to 6 Nm
		Provisions for protective earthing	IS 616: 2010 IEC 60065: 2005 Clause. 15.2	0 to 50 A. 0 to 99.9 V,
		Terminals for external flexible	IS 616: 2010 IEC 60065: 2005	20 cNm to 120 CNm, 1 Nm to 6 Nm
		Cords & for permanent connection to the mains supply	IS 616: 2010 IEC 60065: 2005 Clause. 15.3	20 cNm to 120 CNm, 1 Nm to 6 Nm

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	Audio, Video electronic apparatus	Devices forming A part of the mains plug	IS 616: 2010 IEC 60065: 2005 Clause. 15.4	20 cNm to 120 cNm , 1 Nm to 6 Nm
		Normal Operating Condition	IS 616: 2010 IEC 60065: 2005 Clause. 4.2	62.5 Hz to 16 kHz 0 to 5000 W, 0 to 1000 W,
		External flexible cords	IS 616: 2010 IEC 60065: 2005 Clause. 16	Upto 10 kg 20 cNm to 120 cNm , 1 Nm to 6 Nm, 0 to 150 mm
		Electrical connections & mechanical fixing	IS 616: 2010 IEC 60065: 2005 Clause. 17	20 cNm to 120 cNm , 1 Nm to 6 Nm,
		Mechanical Strength of picture tubes and protection against the effects of implosion	IS 616: 2010 IEC 60065: 2005 Clause. 18	0 to 300 °C 0 to 200 gm
		Stability & mechanical hazards	IS 616: 2010 IEC 60065: 2005 Clause. 19	0 to 90 °
		Wall or ceiling mounting means	IS 616: 2010 IEC 60065: 2005 Clause. 19.6	0 to 10 kg
		Resistance to fire	IS 616: 2010 IEC 60065: 2005 Clause. 20	0 to 400 °C 0 to 60 min

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III. INFORMATION TECHNOLOGY EQUIPMENTS

1.	Information technology equipment - Visual Display unit, Laptop/ Notebook/ Tablets, Printer/ Plotters, Video monitor /LCD/LED/Plasma TVs, Automated data processing machine, Scanner, Wireless Keyboards, Set top boxes, Telephone answering machine, Power adaptors for IT equipment, Mobile Phones, Cash register, Point of sale terminals, Copying Machines/ Duplicators, Smart card readers, Mail processing machines/ Postage machines/ Franking machines, Passport reader, Power banks for use in portable applications	Components	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 1.5	Qualitative
		Input current	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 1.6.2	0 to 20 A 0 to 500 V, 0 to 5000 W,
		Marking and instructions	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 1.7	Qualitative
		Durability	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 1.7.11	Qualitative
		Access to energized parts	IS 13252 (Part 1): 2010 IEC 60950-1: 2005	Qualitative
		Access to ELV wiring	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.1.1.3	0 to 150 mm, 0 to 25 mm,
		Energy hazard	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.1.1.5	60 V/60 A/300 W 0 to 20 μ F, 0 to 500 V
		Discharge of capacitors in equipment	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause -2.1.1.7	0 to 1000 V DC, 0 to 750 V AC, 0 to 25 MHz, 1.2 μ s to 50 s
		SELV circuits	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. -2.2	0 to 1000 V DC 0 to 750 V AC,

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	Information technology equipment - Visual Display unit, Laptop/ Notebook/ Tablets, Printer/ Plotters, Video monitor /LCD/LED/Plasma TVs, Automated data processing machine, Scanner, Wireless	TNV circuits limits	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.3.1	0 to 1000 V DC, 0 to 750 V AC, 60 V/60 A/300 W
	Keyboards, Set top boxes, Telephone answering machine, Power adaptors for IT equipment, Mobile Phones, Cash register, Point of sale terminals, Copying Machines/ Duplicators, Smart card readers, Mail processing machines/ Postage machines/ Franking machines, Passport reader, Power banks for use in portable applications	Connection of TNV circuits to other circuits	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.3.4	0 to 1000 V DC, 0 to 750 V AC, 60 V/60 A/300 W,
		Limited current circuits limits values (Clause. 2.4.2) & limited power sources	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.5	60 V/60 A/300 W 0 to 999.9V, 0 to 20 A, 0.4 kW
		Size of protective earthing & bonding conductor –	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.6.3.2/2.6.3.3)	0 to 150 mm, 0 to 25 mm, 0 to 99.9 V 0 to 50 A
		Resistance of earthing conductors and their terminals	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.6.3.4	0 to 50 A.
		Protection requirement for safety interlocks	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.8.2	Qualitative
		Humidity conditioning	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.9.2	0 to 50 °C , 0 to 98 %RH
		Clearances	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.10.3	Upto 150 mm, Upto 25 mm,

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	Information technology equipment - Visual Display unit, Laptop/ Notebook/ Tablets, Printer/ Plotters, Video monitor /LCD/LED/Plasma TVs, Automated data processing machine, Scanner, Wireless Keyboards, Set top boxes, Telephone answering machine, Power adaptors for IT equipment, Mobile Phones, Cash register, Point of sale terminals, Copying Machines/ Duplicators, Smart card readers, Mail processing machines/ Postage machines/ Franking machines, Passport reader, Power banks for use in portable applications	Creepage distance	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.10.4	0 to 150 mm, 0 to 25 mm,
		Thermal conditioning	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.10.8.2	0 to 100 °C
		Thermal cycling	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 2.10.9	0 to 100 °C
		Wiring connections & supply	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 3.0	0 to 10 kg, 0 to 150 mm, 0 to 25 mm,
		Stability	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.1	0 to 90 °, 0 to 250 N,
		Mechanical Strength	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.2	0 to 250 N,
		Steady force test	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.2.2, 4.2.3, 4.2.4	0 to 250 N,
		Impact test	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.2.5	500 g weight 50 mm dia
		Drop test	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.2.6	13 mm, hardwood on 19 mm on 20 mm

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	Information technology equipment - Visual Display unit, Laptop/ Notebook/ Tablets, Printer/ Plotters, Video monitor /LCD/LED/Plasma TVs, Automated data processing machine, Scanner, Wireless Keyboards, Set top boxes, Telephone answering machine, Power adaptors for IT equipment, Mobile Phones, Cash register, Point of sale terminals, Copying Machines/ Duplicators, Smart card readers, Mail processing machines/ Postage machines/ Franking machines, Passport reader, Power banks for use in portable applications	Stress relief test	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.2.7	0 to 400 °C,
		Mechanical strength for Wall or ceiling mounted equipment	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.2.10	0 to 10 kg.
		Design & construction for Handles & manual controls	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.3.2	0 to 250 N,
		Protection against hazardous moving parts	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.4	Qualitative
		Temperature tests	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.5.2	Ambient to 200 °C
		Resistance to abnormal heat	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.5.5	0 to 400 °C, 20 N 0 to 150 mm,
		Opening in enclosure	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.6	0 to 150 mm 0 to 25 mm,
		Evaluation measures for larger opening	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.6.4.2	Probe-1 mm dia 13 mm length
		Resistance to fire	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 4.7	0 to 1000 °C 0 to 150 mm,
		Touch current & protective conductor current	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 5.1	0.005 mA to 10 mA

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		Protection from hazardous voltages	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 6.1.1	0 to 5mA
		Separation of the telecommunication network from earthing	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 6.1.2	0 to 5 kV
		Impulse test	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 6.2.2.1	0 to 8 kV
		Steady state test	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 6.2.2.2	0 to 5 kV
		Compliance criteria	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause 6.2.2.3	0 to 8 kV
		Impulse test	IS 13252 (Part 1): 2010 IEC 60950-1: 2005 Clause. 7.4.3	0 to 8 kV

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IV. SAFETY TESTING

1.	Microwaves Oven	Marking & Instruction	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 7	Qualitative
		Protection against Electric shock & energy hazards	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 8	4.5 V to 60 V
		Starting of Motor operated Appliances	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 9	20 mΩ to 2 kΩ
		Input	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 10	0 to 5000 watt 0 to 500 V 0 to 30 A
		Temperature Rise	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 11	0 to 200 °C 20 mΩ to 2 kΩ
		Operation under overload condition	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 12	0 to 500 V 0 to 50 A 0 to 999999
		Electrical Insulation and leakage current at operating temperature	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 13	0 to 5 kV 0 to 250 mA 0 to 2000 μA
		Moisture Resistance	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 15	Ambient 98 % RH Ambient 50 °C
		Insulation resistance and Electrical Strength (after Humidity treatment)	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 16	0 to 5 kV 0 to 250 mA 0 to 2000 μA
		Overload protection	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 17	0 to 500 V 0 to 5000 W 0 to 30 A

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	Microwaves Oven	Endurance Test	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 18	0 to 300 V, 0 to 1 A,
		Abnormal Operation	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 19	0 to 500 V, 0 to 5000 W, 0 to 99.9 °C,
		Stability and Mechanical Hazards	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 20	Spring hammer (0.5 J) 500 gm Ball (50 (±)1) mm
		Mechanical Strength	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 21	Force 0 to 980 N, LC: 0.2 N
		Construction	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 22	0 to 200 N, LC=0.1 N (test finger nail) 0 to 150 mm, LC=0.01 mm, 0 to 400 °C, LC=1 °C Temp.75 (±)2 °C
		Internal wiring	IS-302-2-25, 1994 IEC 60335-2-25 Clause. 23	0 to 25 mm, 0 to 150 mm, 0 to 5 kV 0 to 100 mA,
		Components	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 24	Qualitative
		Cord grip and cord guard	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 25	0 to 25 mm, 0 to 150 mm, 0 to 5 kV 0 to 100 Ma, 100 N, 0.25 Nm,

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	Microwaves Oven	Terminals for external conductors	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 26	0 to 25 mm, 0 to 150 mm, 0.2 Nm to 2.5 Nm
		Provision for earthing	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 27	0 to 99.9V, 0 to 50 A,
		Screws and connections	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 28	0 to 150 mm, 0.2 Nm to 2.5 Nm
		Creepage Distances and Clearances	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 29	0 to 150 mm, 0.05 mm to 1.00 mm
		Resistance to heat, time and tracking	IS 302-2-25: 1994 IEC 60335-2-25 Clause. 30	0 to 400 °C, 20 N 0 to 1000 °C, 0 to 600 V 0 to 2.0 A rms
		Resistance to rusting	IS 302-2-25: 1994 Clause. 31 IEC 60335-2-25	0 to 100 °C, Relative Humidity 95 %
2.	Clocks Main operated clocks with rated voltage not exceeding 250V, AC single Phase or DC. Alarm Clock, Clocks controlling radio receivers and like, Spring driven clocks with an electrically operated winding	Marking & Instruction	IS 302-2-26: 1994 Clause. 7 IEC 60335-2-26	Qualitative
		Protection against Electric shock & energy hazards	IS 302-2-26: 1994 Clause. 8 IEC 60335-2-26	4.5 V to 60 V,
		Starting of Motor operated Appliances	IS 302-2-26: 1994 Clause. 9 IEC 60335-2-26	20 mΩ to 2 kΩ
		Input	IS 302-2-26: 1994 Clause. 10 IEC 60335-2-26	0 to 5000 W, 0 to 500 V, 0 to 30 A
		Temperature Rise	IS 302-2-26: 1994 Clause. 11 IEC 60335-2-26	0 to 200 °C, 20 mΩ to 2 kΩ

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	Clocks Main operated clocks with rated voltage not exceeding 250V, AC single Phase or DC. Alarm Clock, Clocks controlling radio receivers and like, Spring driven clocks with an electrically operated winding	Operation under overload condition	IS 302-2-26: 1994 Clause. 12 IEC 60335-2-26	0 to 500 V, 0 to 50 A, 0 to 999999 0 to 1000 W,
		Electrical Insulation and leakage current at operating temperature	IS 302-2-26: 1994 Clause. 13 IEC 60335-2-26	0 to 5 kV 0 to 250 mA, 0 to 2000 μ A,
		Moisture Resistance	IS 302-2-26: 1994 Clause. 15 IEC 60335-2-26	Ambient 98 % RH, Ambient 50 °C,
		Insulation resistance and Electrical Strength (after Humidity treatment)	IS 302-2-26: 1994 Clause. 16 IEC 60335-2-26	0 to 5 kV 0 to 250 mA, 2 M Ω
		Overload protection	IS 302-2-26: 1994 Clause. 17 IEC 60335-2-26	0 to 500 V, 0 to 5000 W, 0 to 30 A,
		Endurance Test	IS 302-2-26: 1994 Clause. 18 IEC 60335-2-26	0 to 300 V, 0 to 1 A
		Abnormal Operation	IS 302-2-26: 1994 Clause. 19 IEC 60335-2-26	0 to 500 V, 0 to 5000 W, 0 to 99.9 °C
		Stability and Mechanical Hazards	IS 302-2-26: 1994 Clause. 20 IEC 60335-2-26	Spring hammer (0.5 J) 500 gm Ball (50 (\pm)1) mm
		Mechanical Strength	IS 302-2-26: 1994 Clause. 21 IEC 60335-2-26	Force 0 to 980 N
		Construction	IS 302-2-26: 1994 Clause. 22 IEC 60335-2-26	Force: 200 N (test finger nail) 0 to 150 mm

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	Clocks Main operated clocks with rated voltage not exceeding 250V, AC single Phase or DC. Alarm Clock, Clocks controlling radio receivers and like, Spring driven clocks with an electrically operated winding	Internal wiring	IS 302-2-26: 1994 Clause. 23 IEC 60335-2-26	0 to 25 mm 0 to 150 mm 0 to 5 kV 0 to 100 mA
		Components	IS 302-2-26: 1994 Clause. 24 IEC 60335-2-26	Qualitative
		Supply connection and external flexible cables and cords	IS 302-2-26: 1994 Clause. 25 IEC 60335-2-26	0 to 25 mm, 0 to 150 mm, 0 to 5 kV 0 to 100 mA. 100 N, 1 Nm to 6 Nm
		Terminals for external conductors	IS 302-2-26: 1994 Clause. 26 IEC 60335-2-26	0 to 25 mm, 0 to 150 mm, 0.2 Nm to 2.5 Nm
		Provision for earthing	IS 302-2-26: 1994 Clause. 27 IEC 60335-2-26	0 to 99.9 V, 0 to 50 A,
		Screws and connections	IS 302-2-26: 1994 Clause. 28 IEC 60335-2-26	0 to 150 mm, 0.2 Nm to 2.5 Nm,
		Creepage Distances and Clearances	IS 302-2-26: 1994 Clause. 29 IEC 60335-2-26	0 to 150 mm, 0.05 mm to 1.00 mm
		Resistance to heat, time and tracking	IS 302-2-26: 1994 Clause. 30 IEC 60335-2-26	0 to 400 °C, 20 N 0 to 1000 °C, 0 to 600 V 0 to 2.0 A
		Resistance to rusting	IS 302-2-26: 1994 Clause. 31 IEC 60335-2-26	0 to 100 °C, Relative Humidity: 95 %

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V.	ELECTRONIC COMPONENT & EQUIPMENT SUB ASSEMBLIES			
1.	AC supplied electronic ballasts for tubular florescent lamps	Classification	IS 13021 (Part 1): 1991 Clause. 6 IEC 60928: 1990	Qualitative
		Marking	IS 13021 (Part 1): 1991 Clause. 7 IEC 60928: 1990	Qualitative
		Terminals	IS 13021 (Part 1): 1991 Clause. 8 IEC 60928: 1990	Qualitative
		Provision for earthing	IS 13021 (Part 1): 1991 Clause. 9 IEC 60928: 1990	Qualitative
		Creepage distances and clearances	IS 13021 (Part 1): 1991 Clause. 10 IEC 60928: 1990	0.05 mm to 1 mm 0 to 200 mm
		Protection against accidental contact with live parts	IS 13021 (Part 1): 1991 Clause. 11 IEC 60928: 1990	0 to 75 V
		Protection against electric shock	IS 13021 (Part 1): 1991 Clause. 12 IEC 60928: 1990	0 to 75 V
		Moisture resistance and insulation	IS 13021 (Part 1): 1991 Clause. 13 IEC 60928: 1990	0 to 100 °C, 20 % to 100 % Rh 0 to ∞ MΩ
		Electric Strength	IS 13021 (Part 1): 1991 Clause. 4 IEC 60928: 1990	0 to 5 kV
		Abnormal Conditions	IS 13021 (Part 1): 1991 Clause. 15 IEC 60928: 1990	0 to 400 °C

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
2.	AC Supplied Electronic Ballasts for Tubular Fluorescent Lamps	Marking	IS 13021 (Part 2): 1991 Clause. 5 IEC 60929: 1990	Qualitative
		General Requirement	IS 13021 (Part 2): 1991 Clause. 6 IEC 60929: 1990	Qualitative
		Starting Conditions	IS 13021 (Part 2): 1991 Clause. 7 IEC 60929: 1990	0 to 200 s
		Operating Conditions	IS 13021 (Part 2): 1991 Clause. 8 IEC 60929: 1990	0 to 600 V, (-)1.00 to (+)1.00
		Circuit Power Factor	IS 13021 (Part 2): 1991 Clause. 9 IEC 60929: 1990	(-)1.00 to (+)1.00
		Supply Current	IS 13021 (Part 2): 1991 Clause. 10 IEC 60929: 1990	0 to 20 A
		Maximum Current in any lead to a cathode	IS 13021 (Part 2): 1991 Clause. 11 IEC 60929: 1990	0 to 20 A
		Current Waveform	IS 13021 (Part 2): 1991 Clause. 12 IEC 60929: 1990	1 to 50 th Order
		Magnetic Screening	IS 13021 (Part 2): 1991 Clause. 13 IEC 60929: 1990	0 to 20 A
		Impedance of Audio Frequencies	IS 13021 (Part 2): 1991 Clause. 14 IEC 60929: 1990	50 Hz to 2 kHz

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	AC Supplied Electronic Ballasts for Tubular Fluorescent Lamps	Mains Transient Over Voltage	IS 13021 (Part 2): 1991 Clause. 15 IEC 60929: 1990	0 to 4000 V
		Operational Tests for Abnormal Conditions	IS 13021 (Part 2): 1991 Clause. 16 IEC 60929: 1990	0 to 400 °C
		Endurance	IS 13021 (Part 2): 1991 Clause. 17 IEC 60929: 1990	0 to 5000 W 0 to 20 A 0 to 9999 h 0 to 9999 count
3.	Ballasts for fluorescent lamps for switch Start circuits	General Design Construction and Workmanship	IS 1534 (Part 1): 1977 Clause. 3 IEC 60082: 1984	Qualitative
		Terminal for external wiring	IS 1534 (Part 1): 1977 Clause. 4 IEC 60082: 1984	0 to 25 mm
		Screws, current-carrying parts and connections	IS 1534 (Part 1): 1977 Clause. 5 IEC 60082: 1984	0 to 6 Nm
		Provision for earthing	IS 1534 (Part 1): 1977 Clause. 6 IEC 60082: 1984	Qualitative
		Creep age distances and clearances	IS 1534 (Part 1): 1977 Clause. 7 IEC 60082: 1984	0.05 mm to 1 mm 0 to 200 mm
		Marking	IS 1534 (Part 1): 1977 Clause. 8 IEC 60082: 1984	Qualitative
		Protection against accidental contacts and electric shock	IS 1534 (Part 1): 1977 Clause. 9.5 IEC 60082: 1984	0 to 75 V
		Voltage across capacitors	IS 1534 (Part 1): 1977 Clause. 9.6 IEC 60082: 1984	0 to 1000 V

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Ballasts for fluorescent lamps foe switch Start circuits	Moisture resistance and insulation	IS 1534 (Part 1): 1977 Clause. 9.7 IEC 60082: 1984	0 to 100.0 °C, 20 to 100 %Rh 0 to 1 GΩ, 0 to 5 kV
		Test for thermal endurance of windings	IS 1534 (Part 1): 1977 Clause. 9.8 IEC 60082: 1984	0 to 20 A, 0 to 199.9 °C 0 to 1999 Ω, 0 to 1 GΩ
		Test for limitations of Ballast Heating	IS 1534 (Part 1): 1977 Clause. 9.9 IEC 60082: 1984	0 to 199.9 °C, 0 to 5 kV
		Test for Mechanical Strength	IS 1534 (Part 1): 1977 Clause. 9.10 IEC 60082: 1984	Qualitative
		Resistance to heat	IS 1534 (Part 1): 1977 Clause. 9.11 IEC 60082: 1984	0 to 400 °C
		Test for resistance to corrosion	IS 1534 (Part 1): 1977 Clause. 9.12 IEC 60082: 1984	Qualitative (Visual & Physical test)
		Performance	IS 1534 (Part 1): 1977 Clause. 9.13 IEC 60082: 1984	0 to 600 V, 0 to 12 kW 0 to 20 A, (-)1.00 to (+)1.00
		Test for Ballast losses	IS 1534 (Part 1): 1977 Clause. 9.14 IEC 60082: 1984	0 to 12 kW 0 to 20 A
4.	DC or AC supplied electronic control gear for LED Modules	Marking	IS 15885 (Part 2/Sec XIII): 2012 Clause. 7	Visual

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	DC or AC supplied electronic control gear for LED Modules	Protection against accidental contact with live parts	IS 15885 (Part 1): 2011 Clause. 8	(0 to 100 V) LC: 1 V
		Terminals Clause	IS 15885 (Part 1): 2011 Clause. 9	0 to 150 mm, LC 0.01 mm 0 to 80 N
		Provision for protective earthing	IS 15885 (Part 1): 2011 Clause. 10	0 to 25 A, LC 0.1 A 0 to 5 V, LC 0.01 V
		Moisture Resistance	IS 15885 (Part 1): 2011 Clause. 11	0 to 96 %, LC:1 % 0 to 199.9 °C, LC: 0.1 °C
		Electric Strength	IS 15885 (Part 1): 2011 Clause. 12	0 to 3 kV LC: 0.1 kV
		Thermal endurance test for winding of ballasts	IS 15885 (Part 1): 2011 Clause. 13	0 to 1000 °C, LC: 1 °C 0 to 200 V, LC: 1 V
		Fault conditions	IS 15885 (Part 1): 2011 Clause. 14	0 to 600 V, 0 to 12 kW 0 to 20 A, (-)1.00 to (+)1.00
		Transformer heating	IS 15885 (Part 1): 2011 Clause. 15	0 to 400 °C LC: 1 °C 0 to 50 A LC: 0.1 A
		Construction	IS 15885 (Part 1): 2011 Clause. 16	Qualitative
		Creepage distance and clearances	IS 15885 (Part 1): 2011 Clause. 17	0 to 150 mm LC: 0.01 mm
		Screws, current-carrying parts and connections	IS 15885 (Part 1): 2011 Clause. 18	1 Nm to 6 Nm 20 cNm to 120 cNm

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	DC or AC supplied electronic control gear for LED Modules	Resistance to heat, fire and tracking	IS 15885 (Part 1): 2011 Clause 19	0 to 1000 °C, LC:1 °C 0 to 200 V, LC:1 V
		Resistance to corrosion	IS 15885 (Part 1): 2011 Clause 20	0 to 250 °C, LC:1 °C Chemical
5.	Cathode Ray Tube Colour Based Data Display Monitor	Marking	IS13384 (Part 1): 1992 Clause 4 IS13384 (Part 2): 1997 Clause 11	Qualitative
	Cathode Ray Tube Monochrome Based Data Display Monitor	Safety Requirement	IS13384 (Part 1): 1992 Clause 6 IS13384 (Part 2): 1997 Clause 5	0 to 300 V, LC:1 V 0 to 5000 W, LC:1 W
		Performance Requirement	IS13384 (Part 1): 1992 Clause 8 IS13384 (Part 2): 1997 Clause 7	0 to 300 V, LC:1 V 0 to 5000 W, LC:1 W
		Environmental Tests	IS13384 (Part 1): 1992 Clause 11 IS13384 (Part 2): 1997 Clause 10	(-)50 °C to (+)50 °C LC 0.1 °C 20 % to 98 % LC-0.1 %
6.	Household Electrical Appliance	General Conditions for Measurements	IEC 62301: 2011	Qualitative
		Measurements	IEC 62301: 2011	0 to 500 V,LC=0.01 Upto 100 V,0.1 V 0 to 999.9 W, LC: 0.1 W 0 to 20 A, LC 0.01 A 0 to 50 Hz, LC 0.01 Hz R=0 to 60 min LC=0.01 s/ 1 s
		Sampling Method	IEC 62301: 2011	0 to 500 V,LC: 0.01 Upto 100 V,0.1 V 0 to 999.9 W, LC0.1 W 0 to 20 A, LC 0.01 A 0 to 50 Hz, LC 0.01 Hz R=0 to 60 min LC=0.01 s/ 1 s

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Household Electrical Appliance	Average reading method (Average power approach)	IEC 62301: 2011	0 to 500 V,LC: 0.01 Upto 100 V,0.1 V 0 to 999.9 W, LC: 0.1 W 0 to 20 A, LC 0.01 A 0 to 50 Hz, LC 0.01 Hz R=0 to 60 min, LC=0.01 s/ 1 s
		Direct Meter Reading Method	IEC 62301: 2011	0to 500 V,LC: 0.01 Upto 100 V,0.1 V 0 to 999.9 W, LC0.1 W 0 to 20 A, LC 0.01 A 0 to 50 Hz, LC 0.01 Hz R=0 to 60 min, LC=0.01 s/ 1 s
7.	Audio, video Equipment	General Method of Measurement	IEC 62087: 2002	0 to 500 V , LC: 0.1 V 0 to 20 A, LC: 0.01 A 0 to 999.9 W, LC: 0.1 W 0 to 60 Min, LC=1 s
		Measuring Condition for Television Receiver	IEC 62087: 2002	RF Signal 1 kHz to 20 MHz Sine wave 1 kHz 1 kHz to 16 kHz output Reading (for flat Response) 20dB V (±)0.5 dB V 0 to 500 V,LC: 0.1 V 0 to 20 A, LC: 0.1 A 0 to 999.9 W,LC: 0.1 W
		Measuring Conditions for Video Recording	IEC 62087: 2002	RF Signal 0 to 500 V, LC: 0.1 V 0 to 20 A, LC: 0.01 A 0 to 999.9 W, LC: 0.1 W

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Household Electrical Appliance	STB	IEC 62087: 2002	RF Signal 1 kHz to 20 MHz Sine wave 1 kHz 1 kHz to 16 kHz output Reading (for flat Response) 20 dB V (±)0.5 dB V 0 to 500 V,LC: 0.1 V 0 to 20 A, LC: 0.1 A 0 to 999.9 W,LC: 0.1 W
		Audio Equipment	IEC 62087: 2002	RF Signal 1 kHz to 20 MHz Sine wave 1 kHz 1 kHz to 16 kHz output Reading (for flat Response) 20dB V (±)0.5 dB V 0 to 500 V,LC: 0.1 V 0 to 20 A, LC: 0.1 A 0 to 999.9 W,LC: 0.1 W
8.	Information Technology Equipments Internal/ External AC-DC and DC-DC Power supplies	Off mode	DTH-K/SOP/ ELECT/ 10 Issue No. 1, Issue Date 25.01.2016 DTH-K/SOP/ ELECT/ 11 Issue No. 1, Issue Date 25.01.2016 (Based on Energy Star, BEE Schedule 14 Version 2 & 5)	0.1 Wh to 500 Wh 5 s to 10 min

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Information Technology Equipments Internal/ External AC-DC and DC-DC Power supplies	Sleep Mode	DTH-K/SOP/ ELECT/ 10 Issue No. 1, Issue Date 25.01.2016	0.1 Wh to 500 Wh 5 s to 10 min
			DTH-K/SOP/ ELECT/ 11 Issue No. 1, Issue Date 25.01.2016 (Based on Energy Star, BEE Schedule 14 Version 2 & 5)	
		Idle State	DTH-K/SOP/ ELECT/ 10 Issue No. 1, Issue Date 25.01.2016	0.1 Wh to 500 Wh 5 s to 10 min
			DTH-K/SOP/ ELECT/ 11 Issue No. 1, Issue Date 25.01.2016 (Based on Energy Star, BEE Schedule 14 Version 2 & 5)	
		Active State	DTH-K/SOP/ ELECT/ 10 Issue No. 1, Issue Date 25.01.2016	0.1 Wh to 500 Wh 5 s to 10 min
			DTH-K/SOP/ ELECT/ 11 Issue No. 1, Issue Date 25.01.2016 (Based on Energy Star, BEE Schedule 14 Version 2 & 5)	
		Idle State	DTH-K/SOP/ ELECT/ 10 Issue No. 1, Issue Date 25.01.2016	0.1 Wh to 500 Wh 5 s to 10 min
			DTH-K/SOP/ ELECT/ 11 Issue No. 1, Issue Date 25.01.2016 (Based on Energy Star, BEE Schedule 14 Version 2 & 5)	
		Full Load	DTH-K/SOP/ ELECT/ 10 Issue No. 1, Issue Date 25.01.2016	0.1 Wh to 500 Wh 5 s to 10 min
			DTH-K/SOP/ ELECT/ 11 Issue No. 1, Issue Date 25.01.2016 (Based on Energy Star, BEE Schedule 14 Version 2 & 5)	

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	Information Technology Equipments Internal/ External AC-DC and DC-DC Power supplies	Active Mode power consumption for single Output power supply	DTH-K/SOP/ ELECT/ 10 Issue No. 1, Issue Date 25.01.2016 DTH-K/SOP/ ELECT/ 11 Issue No. 1, Issue Date 25.01.2016 (Based on Energy Star, BEE Schedule 14 Version 2 & 5) Schedule 14 Version 2, Clause 6	0.1 Wh to 500 Wh 5 s to 10 min	
		Active Mode power consumption for multiple Output power supply	DTH-K/SOP/ ELECT/ 10 Issue No. 1, Issue Date 25.01.2016 DTH-K/SOP/ ELECT/ 11 Issue No. 1, Issue Date 25.01.2016 (Based on Energy Star, BEE Schedule 14 Version 2 & 5)	0.1 Wh to 500 Wh 5 s to 10 min	
		Standby Mode Power consumption	DTH-K/SOP/ ELECT/ 10 Issue No. 1, Issue Date 25.01.2016 DTH-K/SOP/ ELECT/ 11 Issue No. 1, Issue Date 25.01.2016 (Based on Energy Star, BEE Schedule 14 Version 2 & 5)	0.1 Wh to 500 Wh 5 s to 10 min	
VI. POWER STABILISER AND UPS					
1.		Solid state invertors run from storage batteries	High voltage test	IS 13314: 1992 Clause. 7.6	0 to 3 KV, LC 0.1KV
			Insulation resistance test	IS 13314: 1992 Clause. 7.7	2 MΩ to ∞, LC 0.5 MΩ

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2.	Solid state invertors run from storage batteries	No-load test	IS 13314: 1992 Clause. 7.8	0 to 300 V, LC:1 V 0 to 5000 W, LC:1 W
		Output test	IS 13314: 1992 Clause. 7.9	0 to 300 V, LC:1 V 0 to 5000 W, LC:1 W
		Climatic tests	IS 13314: 1992 Clause. 7.10	0 to 96 %, LC:1 % 0 to 199.9 °C, LC: 0.1 °C
		Harmonic contents test	IS 13314: 1992 Clause. 7.11	0 to 50 th harmonic
	Uninterruptible power system (UPS)	Marking	IS 16242 (Part 1): 2014 Clause. 4.7 IEC 62040-2: 2005	Qualitative
		Protection against access to live part	IS 16242 (Part 1): 2014 Clause. 7.4 IEC 62040-2: 2005	20 N
		Power input and Current	IS 16242 (Part 1): 2014 Clause. 4.7.1 IEC 62040-2: 2005	0 to 5000 W, LC: 1 W 0 to 500 V, LC: 1 V 0 to 30 A, LC: 0.01 A
		Heating	IS 16242 (Part 1): 2014 Clause. 7.7 IEC 62040-2: 2005	0 to 200 °C, LC=1 °C
		Leakage current	IS 16242 (Part 1): 2014 Clause. 8.1 IEC 62040-2: 2005	0 to 250 mA, LC: 5 mA
		Electrical strength	IS 16242 (Part 1): 2014 Clause. 8.2 IEC 62040-2: 2005	0 to 5 kV LC:0.1 kV

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Uninterruptible power system (UPS)	Humidity test	IS 16242 (Part 1): 2014 Clause. 8.2 IEC 62040-2: 2005	Ambient 98 %RH, LC: 0.1 %RH Ambient 50 °C, LC: 0.1 °C
		Mechanical Strength (cord anchorage and strain relief)	IS 16242 (Part 1): 2014 Clause. 7 IEC 62040-2: 2005	Force 0 to 980 N, LC: 0.2 N
		Earthing contact resistance	IS 16242 (Part 1): 2014 Clause. 5.3 IEC 62040-2: 2005	0 to 30 A, LC: 0.01 A
		Creep age distance, clearance and distances	IS 16242 (Part 1): 2014 Clause. 3.16 IEC 62040-2: 2005	0 to 150 mm, LC:0.01mm 0.05 mm to 1.00 mm
		Ball pressure test	IS 16242 (Part 1): 2014 Clause. 3.10 IEC 62040-2: 2005	0 to 125 °C 5 mm, 20 N
3.	Stationary cells and Batteries lead-acid type (with Tubular Positive Plate)	Verification of Dimension	IS 6151: 1991 IS 6152: 1991	0 to 150 mm LC: 0.01 mm 0 to 1000 mm LC: 0.5 mm
	Stationary cells and Batteries lead-acid type (with Planet positive Plates)	Test for Capacity	IS 6151: 1991 IS 6152: 1991	0 to 199.9 °C, LC: 0.1 °C 0 to 500 V, LC: 0.01 V 0 to 60 min, LC: 0.01 s
		Test for Voltage during discharge	IS 6151: 1991 IS 6152: 1991	0 to 199.9 °C, LC: 0.1 °C 0 to 500 V, LC: 0.01 V 0 to 60 min, LC: 0.01 s
		Ampere hour and watt-hour Efficiency test	IS 6151: 1991 IS 6152: 1991	0 to 500 V, LC: 0.01 V 0 to 60 min, LC: 0.01 s

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	Stationary cells and Batteries lead-acid type (with Tubular Positive Plate)	Test for loss capacity of Storage	IS 6151: 1991 IS 6152: 1991	0 to 500 V, LC=0.01 V 0 to 60 min, LC=0.01 s
		Endurance test	IS 6151: 1991 IS 6152: 1991	0 to 500 V, LC: 0.01 V 0 to 99999.9, LC: 0.1 V
	Stationary cells and Batteries lead-acid type (with Planet positive Plates)	Checking of Dimension and Terminal	IS 8144: 1997 IS 6303	0 to 150 mm LC: 0.01 mm 0 to 1000 mm LC: 0.5 mm
		Initial Life test	IS 8144: 1997 IS 6303	0 to 99999.9 hr LC: 0.1 hr
		Delayed Life test under dry heat Condition	IS 8144: 1997 IS 6303	0 to 999999.9 hr LC: 0.1 hr
		Leakage test for Batteries Marked Leak Proof	IS 8144: 1997 IS 6303	0 to 500 V, LC=0.01 V
4.	Secondary cells and batteries containing alkaline or other non-acid electrolytes	Continuous Low Rate Charge	IS 16046: 2012 Clause. 4.2.1 IEC 62133: 2002	0 to 500 V, LC: 0.01 V 0 to 60 min LC: 0.01 s
		Vibration	IS 16046: 2012 Clause. 4.2.2 IEC 62133: 2002	0 to 500 V, LC: 0.01 V 0 to 60 min LC: 0.01 s
		Temperature cycling	IS 16046: 2012 Clause. 4.2.4 IEC 62133: 2002	0 to 500 V, LC: 0.01 V 0 to 60 min LC: 0.01 s
		External short circuit	IS 16046: 2012 Clause. 4.3.2 IEC 62133: 2002	0 to 500 V, LC: 0.01 V 0 to 60 min LC: 0.01 s
		Free fall	IS 16046: 2012 Clause. 4.3.3 IEC 62133: 2002	0 to 500 V, LC: 0.01 V 0 to 60 min LC: 0.01 s

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Secondary cells and batteries containing alkaline or other non-acid electrolytes	Mechanical shock	IS 16046: 2012 Clause. 4.3.4 IEC 62133: 2002	0 to 10 Nm LC: 0.01 Nm
		Thermal abuse	IS 16046: 2012 Clause. 4.3.5 IEC 62133: 2002	0 to 500 V, LC: 0.01 V 0 to 60 min LC: 0.01 s
		Crushing of cells	IS 16046: 2012 Clause. 4.3.6 IEC 62133: 2002	0 to 500 V, LC: 0.01 V 0 to 60 Min LC: 0.01 s
		Low pressure	IS 16046: 2012 Clause. 4.3.7 IEC 62133: 2002	0 to 500 V, LC: 0.01 V 0 to 60 min, LC: 0.01 s
		Overcharge for lithium systems	IS 16046: 2012 Clause. 4.3.9 IEC 62133: 2002	0 to 500 V, LC: 0.01 V 0 to 60 min, LC: 0.01 s
		Forced discharge	IS 16046: 2012 Clause. 4.3.10 IEC 62133: 2002	0 to 500 V, LC: 0.01 V 0 to 60 min LC: 0.01 s
		Cell protection against at high charging Rate	IS 16046: 2012 Clause. 4.3.11 IEC 62133: 2002	0 to 500 V, LC: 0.01 V 0 to 60 min, LC: 0.01 s

VII. ENVIRONMENTAL TEST FACILITY

1.	Electronic/ Electrical Products	Cold test	IS 9000 (Part 2/Sec I to IV): 1977 IEC 60068-2-1: 2007	(-)30 °C – Ambient LC: 0.1 °C
		Dry Heat	IS 9000 (Part 3/Sec I to V): 1977 IEC 60068-2-2 : 2007	Ambient to (+) 200 °C LC:0.1 °C
		Damp Heat	IS 9000 (Part 4): 2008 IS 9000 (Part 5/Sec I & II): 1981 IEC 60068-2-3: 1969 IEC 60068-2-4: 1960 IEC 60068-2-30: 2005 IEC 60068-2-38: 2009	20 °C to 90 °C LC: 0.1 °C 20 % to 98 % RH

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S. No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Electronic/ Electrical Products	Change of temperature	IS 9000 (Part 14): 1988 IEC 60068-2-14: 2009	(-)50 °C to (+) 200 °C LC: 0.1 °C
		Thermal Shock test	IS 9000 (Part 14): 1988 IEC 60068-2-14: 2009	(-)50 °C to (+) 200 °C LC: 0.1 °C
-X-X-X-X-X-X-X-X-X-X-X-X-				